



# Power MOSFETS

## DATASHEET

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**LM20B50DGF6A**

Dual N-Channel  
Enhancement Mode MOSFET

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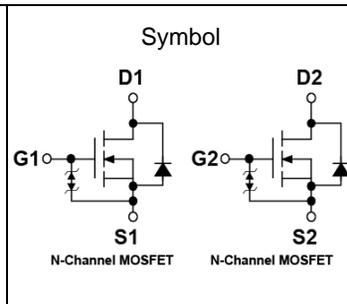
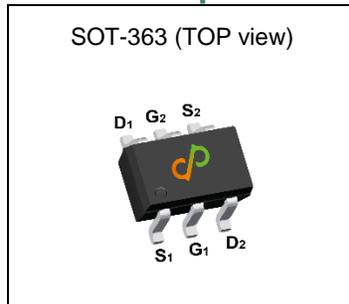


Quality Management Systems

ISO 9001:2015 Certificate

## Dual N-Channel Enhancement Mode MOSFET

### Pin Description



### Ordering Information

Symbol	Dual N-Channel	Unit
V <sub>DSS</sub>	<b>20</b>	<b>V</b>
R <sub>DS(ON)-Max</sub>	<b>300</b>	<b>mΩ</b>
I <sub>D</sub>	<b>0.72</b>	<b>A</b>

### Feature

- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- ESD Protection

### Applications

- Power Management in DC/DC Converters
- Load Switch

### Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM20B50DGF6A	SOT-363	Tape & Reel	3000 / Tape & Reel	1□□□

Note : □□□= Lot Code

### Absolute Maximum Ratings (T<sub>J</sub>=25°C Unless Otherwise Noted)

Symbol	Parameter	Dual N-Channel	Unit	
V <sub>DSS</sub>	Drain-Source Voltage	20	V	
V <sub>GSS</sub>	Gate-Source Voltage	±12		
T <sub>J</sub>	Maximum Junction Temperature	150	°C	
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C	
I <sub>DM</sub> <sup>①</sup>	Pulse Drain Current Tested	T <sub>A</sub> =25°C	0.9	A
I <sub>D</sub> <sup>①</sup>	Continuous Drain Current	T <sub>A</sub> =25°C	0.72	A
		T <sub>A</sub> =70°C	0.57	
P <sub>D</sub>	Maximum Power Dissipation	T <sub>A</sub> =25°C	0.25	W
		T <sub>A</sub> =70°C	0.16	

### Thermal Characteristics

Symbol	Parameter	Rating	Unit	
R <sub>θJA</sub> <sup>③</sup>	Thermal Resistance-Junction to Ambient	Steady State	500	°C/W

Note ① : Max. current is limited by Bonding wire

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150°C

Note ③ : Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.

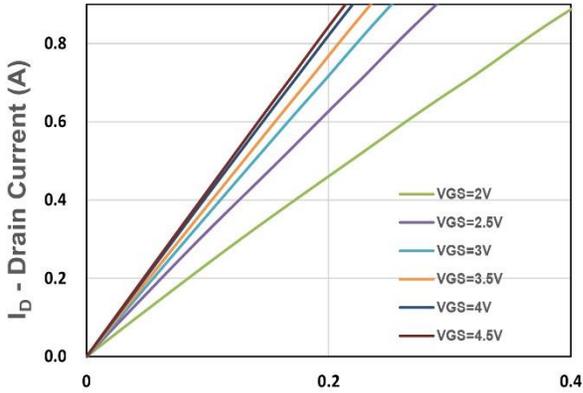
## Dual N-Channel Electrical Characteristics (T<sub>J</sub>=25°C Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static Electrical Characteristics</b>						
<b>BV<sub>DSS</sub></b>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>DS</sub> =250uA	20	-	-	V
<b>I<sub>DSS</sub></b>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =16V, V <sub>GS</sub> =0V	-	-	1	uA
<b>V<sub>GS(th)</sub></b>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>DS</sub> =250uA	0.5	0.75	1	V
<b>I<sub>GSS</sub></b>	Gate Leakage Current	V <sub>GS</sub> =±12V, V <sub>DS</sub> =0V	-	-	±10	uA
<b>R<sub>DS(ON)</sub></b> <sup>④</sup>	Drain-Source On-state Resistance	V <sub>GS</sub> =4.5V, I <sub>DS</sub> =0.6A	-	245	300	mΩ
		V <sub>GS</sub> =2.5V, I <sub>DS</sub> =0.4A	-	310	400	
		V <sub>GS</sub> =1.8V, I <sub>DS</sub> =0.35A	-	420	580	
<b>gfs</b>	Forward Transconductance	V <sub>DS</sub> =3V, I <sub>DS</sub> =0.3A	-	0.9	-	S
<b>Dynamic Characteristics</b> <sup>⑥</sup>						
<b>C<sub>iss</sub></b>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =10V, Freq.=1MHz	-	40	-	pF
<b>C<sub>oss</sub></b>	Output Capacitance		-	17	-	
<b>C<sub>rss</sub></b>	Reverse Transfer Capacitance		-	9.9	-	
<b>td(ON)</b>	Turn-on Delay Time	V <sub>GS</sub> =4.5V, V <sub>DS</sub> =10V, I <sub>D</sub> =2A, R <sub>GEN</sub> =6Ω	-	1.2	-	nS
<b>t<sub>r</sub></b>	Turn-on Rise Time		-	24.5	-	
<b>t<sub>d(OFF)</sub></b>	Turn-off Delay Time		-	13.6	-	
<b>t<sub>f</sub></b>	Turn-off Fall Time		-	14.6	-	
<b>Q<sub>g</sub></b>	Total Gate Charge	V <sub>GS</sub> =2.5V, V <sub>DS</sub> =10V I <sub>D</sub> =1A	-	0.54	-	nC
<b>Q<sub>g</sub></b>	Total Gate Charge	V <sub>GS</sub> =4.5V, V <sub>DS</sub> =10V, I <sub>D</sub> =1A	-	1	-	
<b>Q<sub>gs</sub></b>	Gate-Source Charge		-	0.3	-	
<b>Q<sub>gd</sub></b>	Gate-Drain Charge		-	0.1	-	
<b>Source-Drain Characteristics</b>						
<b>V<sub>SD</sub></b> <sup>④</sup>	Diode Forward Voltage	I <sub>SD</sub> =0.3A, V <sub>GS</sub> =0V	-	0.75	1.1	V
<b>t<sub>rr</sub></b>	Reverse Recovery Time	I <sub>F</sub> =1A, V <sub>R</sub> =10V	-	9.2	-	nS
<b>Q<sub>rr</sub></b>	Reverse Recovery Charge	di <sub>F</sub> /dt=100A/μs	-	0.82	-	nC

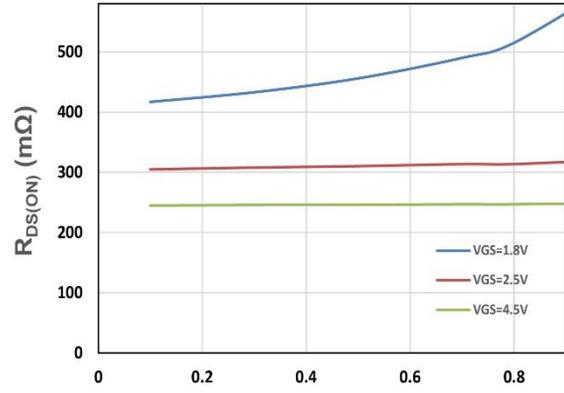
Note ④ : Pulse test (pulse width 300us, duty cycle 2%).

Note ⑤ : Guaranteed by design, not subject to production testing

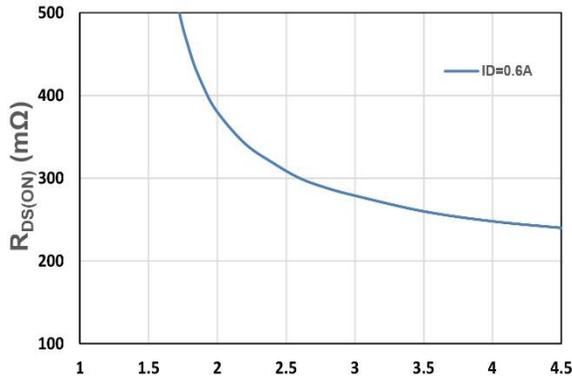
## N-Channel Typical Characteristics



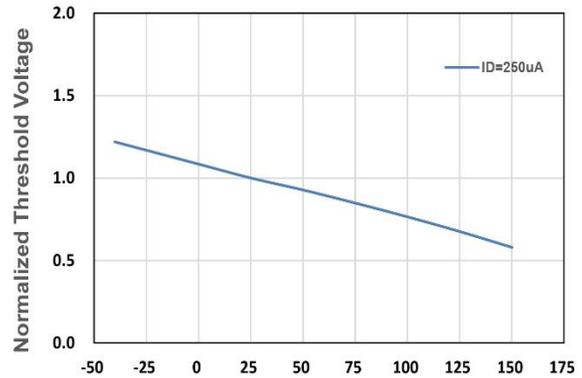
$V_{DS}$  - Drain - Source Voltage (V)  
Figure 1. Output Characteristics



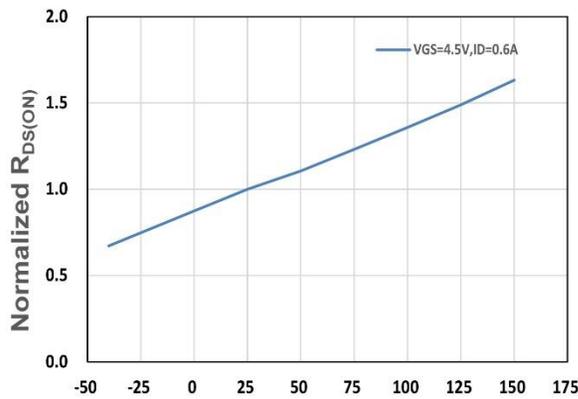
$I_D$  - Drain Current (A)  
Figure 2. On-Resistance vs. ID



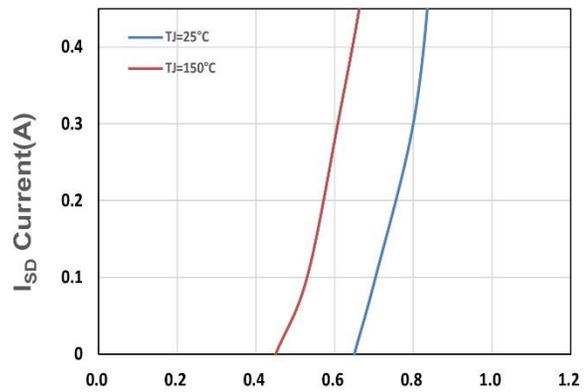
$V_{GS}$  - Gate - Source Voltage (V)  
Figure 3. On-Resistance vs. VGS



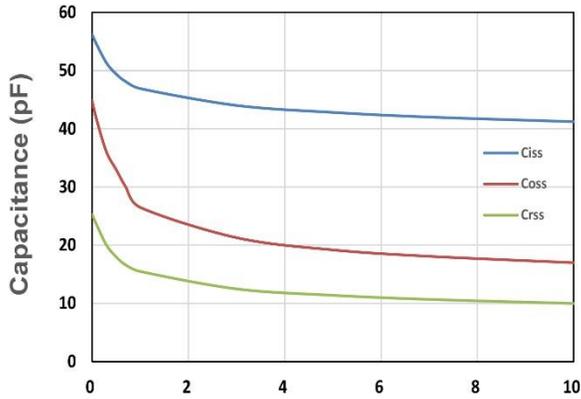
$T_j$ , Junction Temperature( $^{\circ}C$ )  
Figure 4. Gate Threshold Voltage



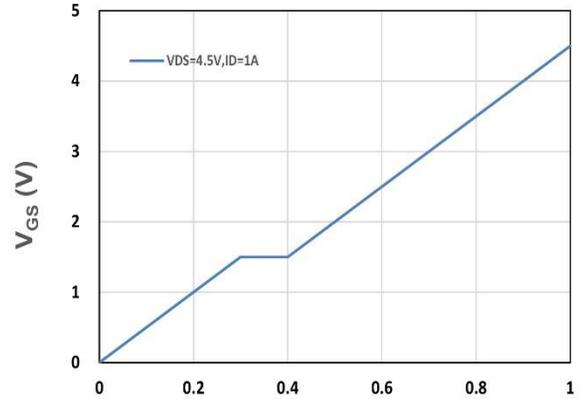
$T_j$ , Junction Temperature( $^{\circ}C$ )  
Figure 5. Drain-Source On Resistance



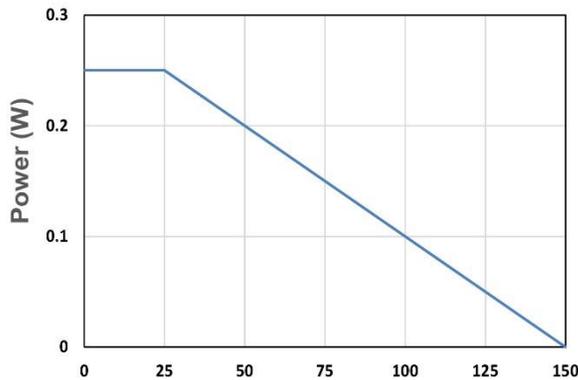
$V_{SD}$ , Source-Drain Voltage(V)  
Figure 6. Source-Drain Diode Forward



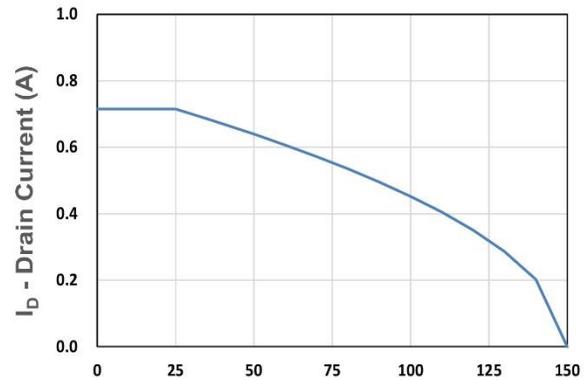
$V_{DS}$  - Drain - Source Voltage (V)  
Figure 7. Capacitance



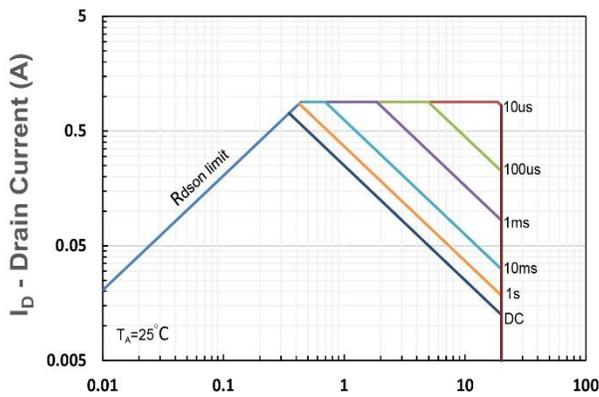
$Q_g$ , Total Gate Charge (nC)  
Figure 8. Gate Charge Characteristics



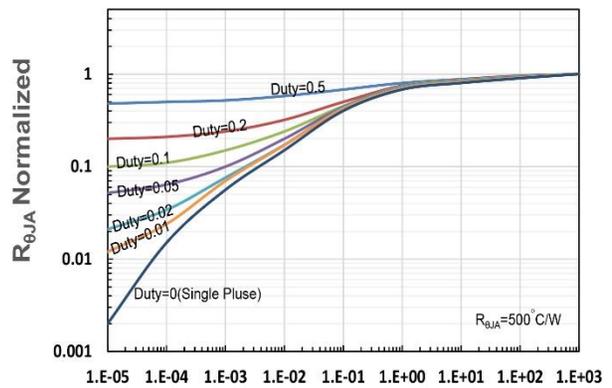
$T_A$  - Ambient Temperature (°C)  
Figure 9. Power Dissipation



$T_A$  - Ambient Temperature (°C)  
Figure 10. Drain Current



$V_{DS}$  - Drain-Source Voltage (V)  
Figure 11. Safe Operating Area



$t_1$ , Square Wave Pulse Duration(s)  
Figure 12.  $R_{\theta JA}$  Transient Thermal Impedance